

AUIRLR2908

HEXFET® Power MOSFET

Features

- Advanced Planar Technology
- Logic-Level Gate Drive
- Low On-Resistance
- 175°C Operating Temperature
- · Fast Switching

Description

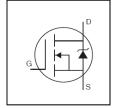
- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Tjmax

Specifically designed for Automotive applications, this Stripe Planar design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon

area. This benefit combined with the fast switching speed and

ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other

- · Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}		80V
R _{DS(on)}	typ.	22.5m $Ω$
	max.	28mΩ
I _{D (Silicon Lin}	nited)	39A®
I _{D (Package L}		30A

D G D-Pak AUIRLR2908

G	D	S
Gate	Drain	Source

AUIRLR2908TRI

applications				
Base next number	Dookogo Typo	Standard Pack		Oudeveble Dout Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
ALUDI DOGGO	D. Dale	Tube	75	AUIRLR2908
AUIRLR2908	D-Pak			

3000

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Tape and Reel Left

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	399	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	28	A
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited) 30		
I _{DM}	Pulsed Drain Current ①	150	
P _D @T _C = 25°C	Maximum Power Dissipation	120	W
	Linear Derating Factor	0.77	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	180	!
E _{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ⑦	250	- mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.3	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
_	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		1.3	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ®		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

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2017-10-09

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	80			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.085		V/°C	Reference to 25°C, I _D = 1mA
D	Static Prain to Source On Registance		22.5	28		$V_{GS} = 10V, I_D = 23A $ ④
$R_{DS(on)}$	Static Drain-to-Source On-Resistance		25	30	mΩ	$V_{GS} = 4.5V, I_D = 20A$ @
$V_{GS(th)}$	Gate Threshold Voltage	1.0		2.5	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	35			S	$V_{DS} = 25V, I_D = 23A $ ④
ı	Drain to Source Leakage Current			20	μA	$V_{DS} = 80V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			200	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-200	ПА	V _{GS} = -16V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Total Gate Charge		22	33		I _D = 23A
Gate-to-Source Charge		6.0	9.1	nC	$V_{DS} = 64V$
Gate-to-Drain Charge		11	17		V _{GS} = 4.5V@
Turn-On Delay Time		12			$V_{DD} = 40V$
Rise Time	_	95		no	I _D = 23A
Turn-Off Delay Time		36		115	$R_G = 8.3\Omega$
Fall Time		55			V _{GS} = 4.5V@
Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
Internal Source Inductance		7.5			from package and center of die contact:
Input Capacitance		1890			$V_{GS} = 0V$
Output Capacitance		260			V _{DS} = 25V
Reverse Transfer Capacitance		35		nΕ	f = 1.0MHz
Output Capacitance		1920		рΓ	$V_{GS} = 0V$, $V_{DS} = 1.0V$ $f = 1.0MHz$
Output Capacitance		170			$V_{GS} = 0V$, $V_{DS} = 64V$ $f = 1.0MHz$
Effective Output Capacitance		310			V_{GS} = 0V, V_{DS} = 0V to 64V
	Gate-to-Source Charge Gate-to-Drain Charge Furn-On Delay Time Rise Time Furn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance Reverse Transfer Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance	Gate-to-Source Charge ————————————————————————————————————	Gate-to-Source Charge — 6.0 Gate-to-Drain Charge — 11 Furn-On Delay Time — 12 Rise Time — 95 Furn-Off Delay Time — 36 Fall Time — 55 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 260 Reverse Transfer Capacitance — 35 Output Capacitance — 1920 Output Capacitance — 170	Gate-to-Source Charge — 6.0 9.1 Gate-to-Drain Charge — 11 17 Furn-On Delay Time — 12 — Rise Time — 95 — Furn-Off Delay Time — 36 — Fall Time — 55 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 1890 — Output Capacitance — 260 — Dutput Capacitance — 35 — Output Capacitance — 1920 — Output Capacitance — 170 —	Gate-to-Source Charge — 6.0 9.1 nC Gate-to-Drain Charge — 11 17 Furn-On Delay Time — 12 — Rise Time — 95 — Furn-Off Delay Time — 36 — Fall Time — 55 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 1890 — Output Capacitance — 35 — Output Capacitance — 1920 — Output Capacitance — 170 —

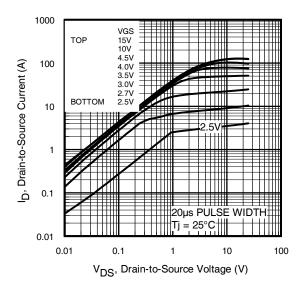
Diode Characteristics

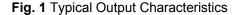
	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			399	_	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			150		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 23A, V_{GS} = 0V $
t _{rr}	Reverse Recovery Time		75	110	ns	$T_J = 25^{\circ}C$, $I_F = 23A$, $V_{DD} = 25V$
Q_{rr}	Reverse Recovery Charge		210	310	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsio	turn-or	time is	negligil	ole (turn-on is dominated by L _S +L _D)

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:loss_def} \ensuremath{\Im} \quad I_{SD} \leq 23A, \ di/dt \leq 400A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width ≤ 1.0 ms; duty cycle $\leq 2\%$.
- \circ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- \odot This value determined from sample failure population, starting T_J = 25°C, L = 0.71mH, R_G = 25 Ω , I_{AS} = 23A, V_{GS} =10V.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ® R_θ is measured at T_J approximately 90°C.







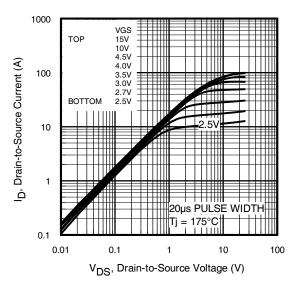


Fig. 2 Typical Output Characteristics

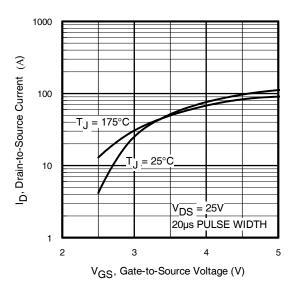


Fig. 3 Typical Transfer Characteristics

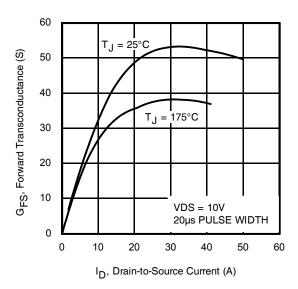


Fig. 4 Typical Forward Trans conductance Vs. Drain Current



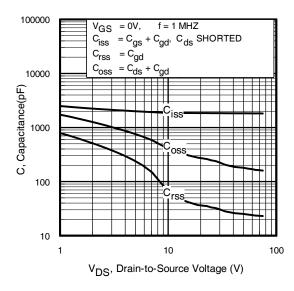


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

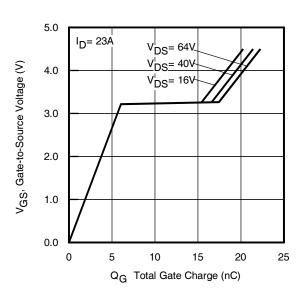


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

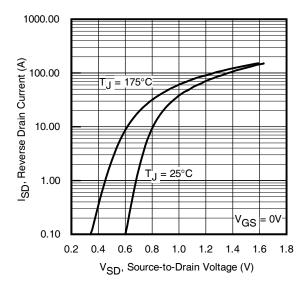


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

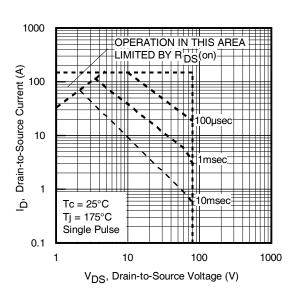
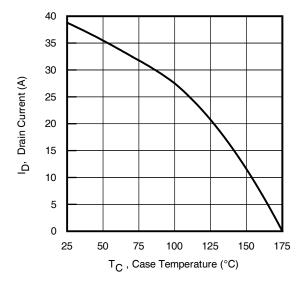


Fig 8. Maximum Safe Operating Area





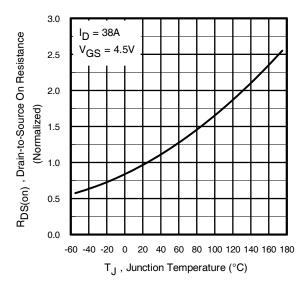


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

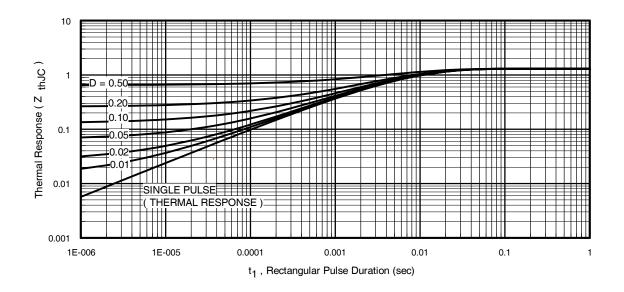


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



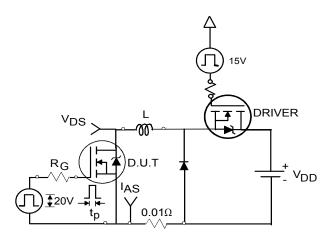


Fig 12a. Unclamped Inductive Test Circuit

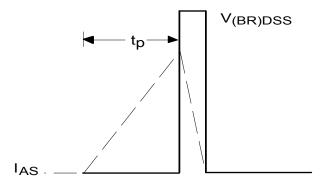


Fig 12b. Unclamped Inductive Waveforms

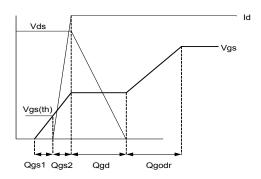


Fig 13a. Gate Charge Waveform

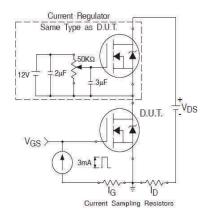


Fig 13b. Gate Charge Test Circuit

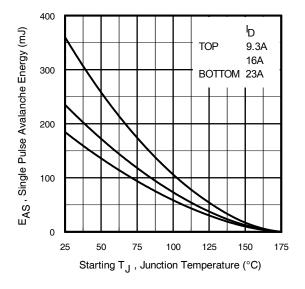


Fig 12c. Maximum Avalanche Energy vs. Drain Current

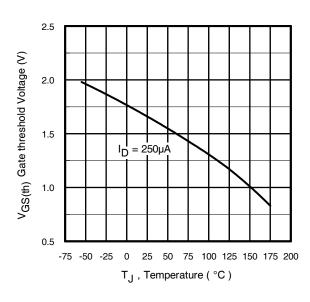


Fig 14. Threshold Voltage Vs. Temperature



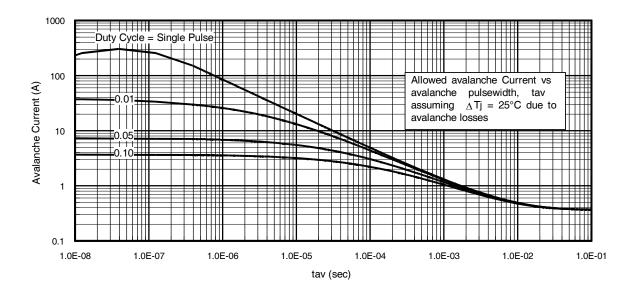


Fig 15. Typical Avalanche Current Vs. Pulse width

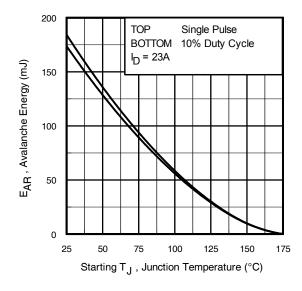


Fig 16. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2 \Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



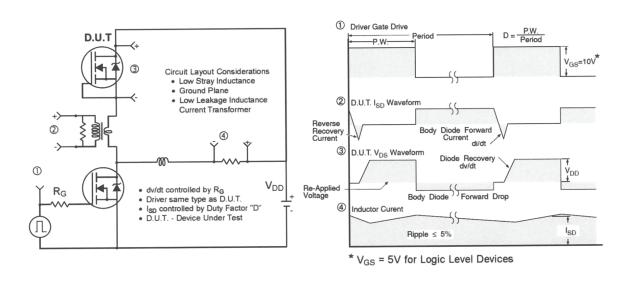


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

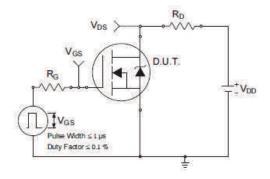


Fig 18a. Switching Time Test Circuit

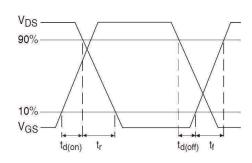
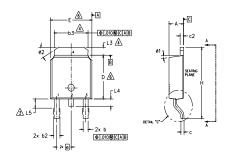


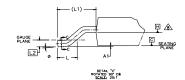
Fig 18b. Switching Time Waveforms

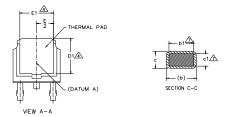


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S					N		
Y M		DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	2.18	2.39	.086	.094			
A1	-	0.13	-	.005			
b	0.64	0.89	.025	.035			
ь1	0.65	0.79	.025	.031	7		
b2	0.76	1.14	.030	.045			
b3	4.95	5.46	.195	.215	4		
С	0.46	0.61	.018	.024			
c1	0.41	0.56	.016	.022	7		
c2	0.46	0.89	.018	.035			
D	5.97	6.22	.235	.245	6		
D1	5.21	-	.205	-	4		
Ε	6.35	6.73	.250	.265	6		
E1	4.32	-	.170	-	4		
e	2.29	BSC	.090	BSC			
Н	9.40	10.41	.370	.410			
L	1.40	1.78	.055	.070			
L1	2.74	BSC	.108	REF.			
L2	0.51	BSC	.020	BSC			
L3	0.89	1.27	.035	.050	4		
L4	-	1.02	-	.040			
L5	1.14	1.52	.045	.060	3		
ø	0.	10°	0,	10°			
ø1	0,	15*	0,	15*			
ø2	25*	35°	25*	35*			

LEAD ASSIGNMENTS

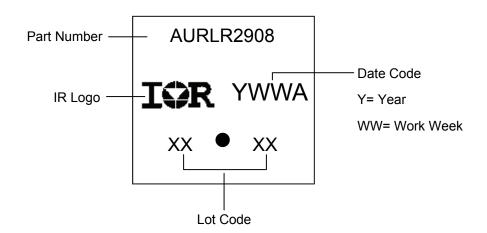
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

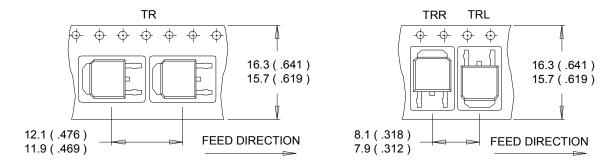
- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 3.- EMITTER 4.- COLLECTOR

D-Pak (TO-252AA) Part Marking Information



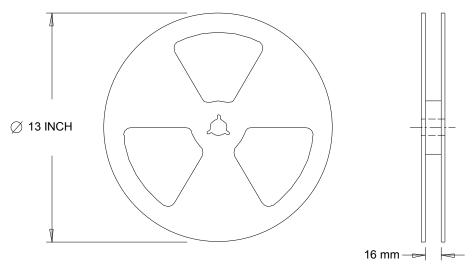


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.



Qualification Information

		T				
		Automotive				
		(per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level		D-Pak	MSL1			
		Class M3 (+/- 400V) [†]				
	Machine Model	AEC-Q101-002				
FOR	Liverage Dady Madal	Class H1C (+/-1500V) †				
ESD	Human Body Model	AEC-Q101-001				
	Charried Davies Medal	Class C5 (+/-2000V) [†]				
Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes				

[†] Highest passing voltage.

Revision History

Date	Comments			
12/11/2015	 Updated datasheet with corporate template Corrected ordering table on page 1. Corrected typo R_{0JA} (PCB mount) from "40°C/W" to "50°C/W" on page 1. 			
10/09/2017	Corrected typo error on part marking on page 9.			

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